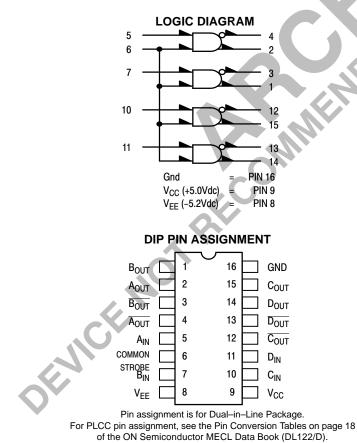
Quad TTL to MECL Translator

The MC10124 is a quad translator for interfacing data and control signals between a saturated logic section and the MECL section of digital systems. The MC10124 has TTL compatible inputs, and MECL complementary open–emitter outputs that allow use as an inverting/ non–inverting translator or as a differential line driver. When the common strobe input is at the low logic level, it forces all true outputs to a MECL low logic state and all inverting outputs to a MECL high logic state.

Power supply requirements are ground, +5.0 Volts, and -5.2 Volts. Propagation delay of the MC10124 is typically 3.5 ns. The dc levels are standard or Schottky TTL in, MECL 10,000 out.

An advantage of this device is that TTL level information can be transmitted differentially, via balanced twisted pair lines, to the MECL equipment, where the signal can be received by the MC10115 or MC10116 differential line receivers. The MC10124 is useful in computers, instrumentation, peripheral controllers, test equipment, and digital communications systems.

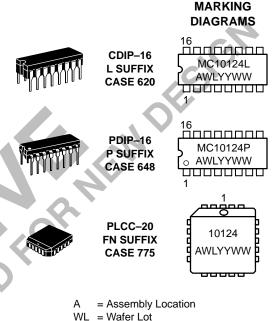
- $P_D = 380 \text{ mW typ/pkg}$ (No Load)
- $t_{pd} = 3.5$ ns typ (+ 1.5 Vdc in to 50% out)
- $t_r, t_f = 2.5 \text{ ns typ} (20\% 80\%)$





ON Semiconductor

http://onsemi.com



VVL = VVater LotYY = Year

YY = Year WW = Work Week

ORDERING INFORMATION

Device	Package	Shipping
MC10124L	CDIP-16	25 Units / Rail
MC10124P	PDIP-16	25 Units / Rail
MC10124FN	PLCC-20	46 Units / Rail

ELECTRICAL CHARACTERISTICS

			Test Limits							
		Pin Under	-30	D∘C		+25°C		+8	5°C	
Characteristic	Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Negative Power Supply Drain Current	ΙE	8		72			66		72	mAdo
Positive Power Supply	I _{CCH}	9		16			16		18	mAdo
Drain Current	I _{CCL}	9		25			25		25	mAdo
Reverse Current	I _R	6 7		200 50			200 50		200 50	μAdo
Forward Current	١ _F	6 7		-12.8 -3.2			-12.8 -3.2		-12.8 -3.2	mAdo
Input Breakdown Voltage	BV _{in}	6 7	5.5 5.5		5.5 5.5			5.5 5.5	C	Vdc
Clamp Input Voltage	VI	6 7		-1.5 -1.5			-1.5 -1.5		-1.5 -1.5	Vdc
High Output Voltage	V _{OH}	1 3	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
Low Output Voltage	V _{OL}	1 3	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc
High Threshold Voltage	V _{OHA}	1 3	-1.080 -1.080		-0.980 -0.980		S	-0.910 -0.910		Vdc
Low Threshold Voltage	V _{OLA}	1 3		-1.655 -1.655		\$	-1.630 -1.630		-1.595 -1.595	Vdc
Switching Times (50Ω Load)						O.				ns
Propagation Delay (+3.5Vdc to 50%) ¹	t_{6+1+} t_{6-1-} t_{7+1+} t_{7-1-} t_{7+3-} t_{7-3+}	1 1 1 3 3	1.5 1.0 1.5 1.0 1.5 1.0	6.8 6.0 6.8 6.0 6.8 6.0	1.0 1.0 1.0 1.0 1.0 1.0	3.5 3.5 3.5 3.5 3.5 3.5 3.5	6.0 6.0 6.0 6.0 6.0 6.0	1.0 1.5 1.0 1.5 1.0 1.5	6.0 6.8 6.0 6.8 6.0 6.8	
Rise Time (20 to 80%)	t ₁₊	1	1.0	4.2	1.1	2.5	3.9	1.1	4.3	
Fall Time (20 to 80%)	t ₁₋	1	1.0	4.2	1.1	2.5	3.9	1.1	4.3	

See switching time test circuit. Propagation delay for this circuit is specified from +1.5Vdc in to the 50% point on the output waveform. The +3.5Vdc is shown here because all logic and supply levels are shifted 2 volts positive.

ELECTRICAL CHARACTERISTICS (continued)

OFVICENO

			TEST VOLTAGE VALUES (Volts)					
	@ Test Te	mperature	VIH	V _{ILmax}	V _{IHA} ,	V _{ILA} ,	V _F	
		–30°C	+4.0	+0.40	+2.00	+1.10	+0.40	
	+25°C			+0.40	+1.80	+1.10	+0.40	
		+85°C	+4.0	+0.40	+1.80	+0.90	+0.40	
		Pin	TEST VO					
Characteristic	Symbol	Under Test	VIH	V _{ILmax}	V _{IHA} ,	V _{ILA} ,	V _F	Gnd
Negative Power Supply Drain Current	Ι _Ε	8						16
Positive Power Supply Drain	I _{CCH}	9	5,6,7,10,11					16
Current	I _{CCL}	9						5,6,7,10,11,1
Reverse Current	I _R	6 7					5,7,10,11 6	16 16
Forward Current	I _F	6 7	5,7,10,11 6				6 7	16 16
Input Breakdown Voltage	BV _{in}	6 7					O	5,7,10,11,10 6,16
Clamp Input Voltage	VI	6 7						16 16
High Output Voltage	V _{OH}	1 3	6,7	6,7				16 16
Low Output Voltage	V _{OL}	1 3	6,7	6,7	.0			16 16
High Threshold Voltage	V _{OHA}	1 3	6 6		7	7		16 16
Low Threshold Voltage	V _{OLA}	1	6 6		7	7		16 16
Switching Times (50Ω Load)			+6.0 V	Pulse In	Pulse Out			+2.0 V
Propagation Delay	t ₆₊₁₊	1	7 7	6	1			16
(+3.5Vdc to 50%) ¹	t ₆₋₁₋			6	1			16
	t ₇₊₁₊		6 6	7 7	1			16 16
	t ₇₋₁₋	3	6	7	1 3			16
	t _{7+3–} t _{7–3+}	3	6	7	3			16
Rise Time (20 to 80%)	t ₁₊		6	7	1			16
Fall Time (20 to 80%)	t ₁₋		6	7	1			16

1. See switching time test circuit. Propagation delay for this circuit is specified from +1.5Vdc in to the 50% point on the output waveform. The +3.5Vdc is shown here because all logic and supply levels are shifted 2 volts positive.

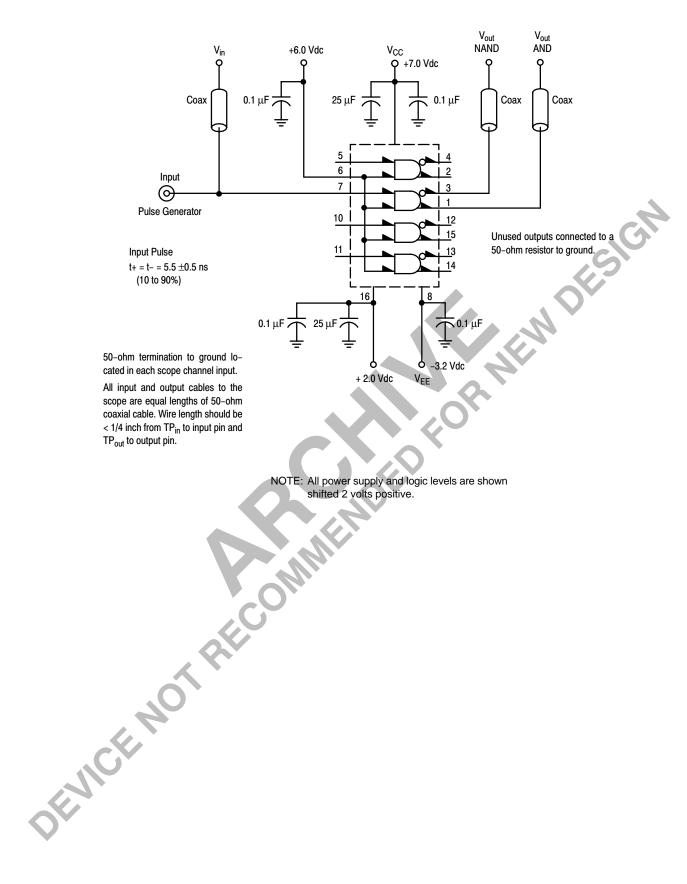
ELECTRICAL CHARACTERISTICS (continued)

			TEST VOL	TAGE VALU	JES (Volts)	(m	A)		
	@ Test Te	mperature	V _R	V _{CC}	V _{EE}	lı	l _{in}		
		–30°C	+2.40	+5.00	-5.2	-10	+1.0		
		+25°C	+2.40	+5.00	-5.2	-10	+1.0		
		+85°C	+2.40	+5.00	-5.2	-10	+1.0		
		Pin	TEST V	TEST VOLTAGE APPLIED TO PINS LISTED BELOW					
Characteristic	Symbol	Under Test	V _R	V _{CC}	V _{EE}	I _I	l _{in}	Gnd	
Negative Power Supply Drain Current	Ι _Ε	8		9	8			16	
Positive Power Supply Drain	I _{CCH}	9		9	8			16	
Current	I _{CCL}	9		9	8			5,6,7,10,11,10	
Reverse Current	I _R	6 7	6 7	9 9	8 8			16 16	
Forward Current	١ _F	6 7		9 9	8 8			16 16	
Input Breakdown Voltage	BV _{in}	6 7		9 9	8 8		6 7	5,7,10,11,16 6,16	
Clamp Input Voltage	VI	6 7		9 9	8 8	6 7		16 16	
High Output Voltage	V _{OH}	1 3		9 9	8 8			16 16	
Low Output Voltage	V _{OL}	1 3		9 9	8			16 16	
High Threshold Voltage	V _{OHA}	1 3		9 9	8 8			16 16	
Low Threshold Voltage	V _{OLA}	1		9 9	8 8			16 16	
Switching Times (50Ω Load				+7.0 V	–3.2 V			+2.0 V	
Propagation Delay (+3.5Vdc to 50%)'	$\begin{array}{c} t_{6+1+} \\ t_{6-1-} \\ t_{7+1+} \\ t_{7-1-} \\ t_{7+3-} \\ t_{7-3+} \end{array}$	1 1 1 3 3	AF.	9 9 9 9 9 9	8 8 8 8 8 8			16 16 16 16 16 16	
Rise Time (20 to 80%)		Н		9	8			16	
Fall Time (20 to 80%)	t ₁₋	1		9	8			16	

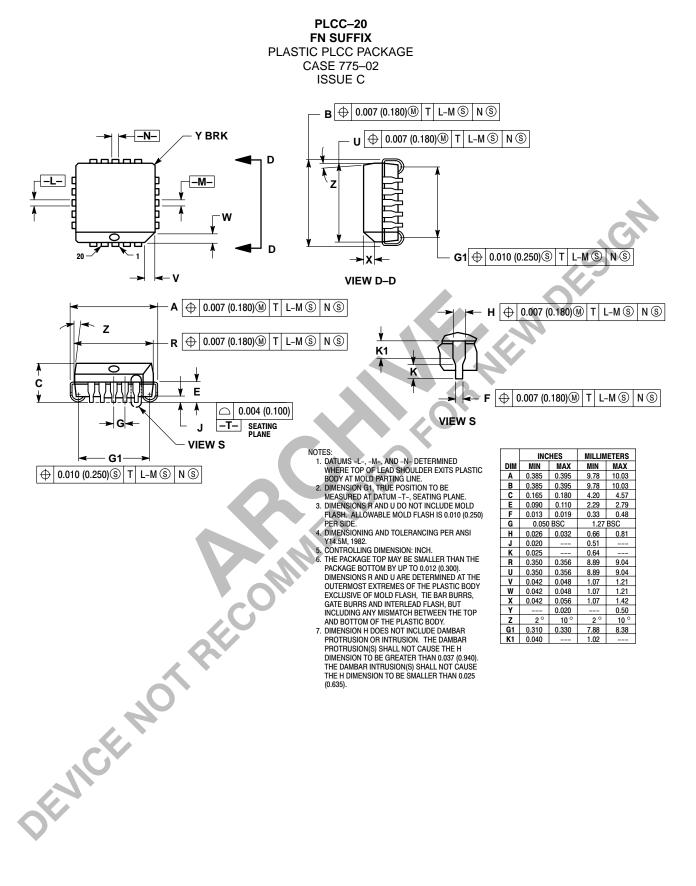
 See switching time test circuit. Propagation delay for this circuit is specified from +1.5Vdc in to the 50% point on the output waveform. The +3.5Vdc is shown here because all logic and supply levels are shifted 2 volts positive.

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50–ohm resistor to –2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

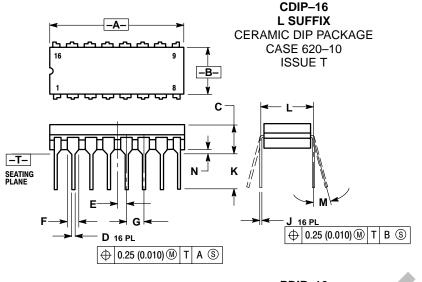
SWITCHING TIME TEST CIRCUIT



PACKAGE DIMENSIONS



PACKAGE DIMENSIONS



NOTES:

DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: INCH.
 DIMENSION L TO CENTER OF LEAD WHEN FOOMED DRAWLES

DIMENSION LTO CENTER OF LEAD WHEN FORMED PARALLEL.
 DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

	INC	HES	MILLIMETERS			
DIM	MIN	MAX	MIN	MAX		
Α	0.750	0.785	19.05	19.93		
В	0.240	0.295	6.10	7.49		
С		0.200		5.08		
D	0.015	0.020	0.39	0.50		
Е	0.050	BSC	1.27 BSC			
F	0.055	0.065	1.40	1.65		
G	0.100	BSC	2.54 BSC			
Н	0.008	0.015	0.21	0.38		
κ	0.125	0.170	3.18	4.31		
Г	0.300 BSC		7.62	BSC		
Μ	0 °	15 °	0 °	15°		
Ν	0.020	0.040	0.51	1.01		

-A-<u>ሳ ስ ስ ስ</u> 16 В 0 L $\Box \Box$ ι, հո - C S -T- SEATING PLANE H G **D** 16 PL

PDIP-16 **P SUFFIX** PLASTIC DIP PACKAGE CASE 648-08 ISSUE R

NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL. 4. DIMENSION B DOES NOT INCLUDE MOLD FLASH. 5. ROUNDED CORNERS OPTIONAL

	INC	HES	MILLIN	IETERS			
DIM	MIN MAX		MIN	MAX			
Α	0.740	0.770	18.80	19.55			
В	0.250	0.270	6.35	6.85			
С	0.145	0.175	3.69	4.44			
D	0.015	0.021	0.39	0.53			
F	0.040	0.70	1.02	1.77			
G	0.100	BSC	2.54 BSC				
Н	0.050	BSC	1.27 BSC				
J	0.008	0.015	0.21	0.38			
ĸ	0.110	0.130	2.80	3.30			
L	0.295	0.305	7.50	7.74			
Μ	0°	10 °	0 °	10 °			
S	0.020	0.040	0.51	1.01			

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